

EFFECTS OF DOPANTS ON FIELD APPLIED METAL INDUCED LATERAL CRYSTALLIZATION RATE

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Polycrystalline silicon thin film transistors (poly-Si TFTs) technology is very attractive for the applications of active matrix liquid crystal devices (AM-LCDs) with integrated peripheral driver circuits fabricated on glass substrates. So many works have been concentrated on lowering the crystallization temperature of a-Si films. Metal induced lateral crystallization (MILC) process has been previously introduced, by which the amorphous silicon thin films can be crystallized below 500°C. It has already reported that applying electric field during MILC enhances MILC rate against field direction. In this works, the effects of dopants on the rate and behavior of field-applied-MILC were investigated. We have doped a-Si with B₂H₆ or PH₃ gas by Ion Mass Doping System and We applied electric field (100V/cm) during MILC. When a-Si was doped with PH₃, MILC rate has also increased against field direction, while MILC rate has increased toward field direction when a-Si was doped with B₂H₆.

The role of dopants in Field-Applied-MILC(FALC) rate will be discussed in terms of Ni ion and charged Ni vacancy (NINV) Hopping Model.

Reference

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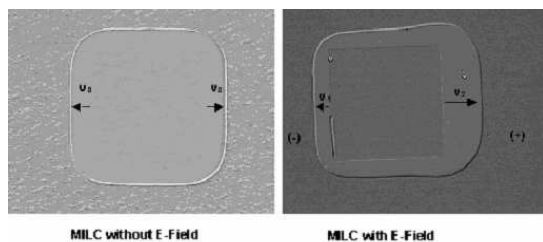


Fig. 1 MILC and FALC aspect of Intrinsic sample

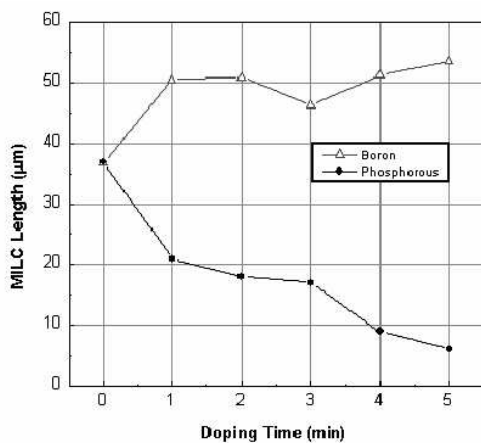


Fig. 2 MILC growth Length variation by different dopant and doping time (550°C 5hr annealing at vacuum furnace)

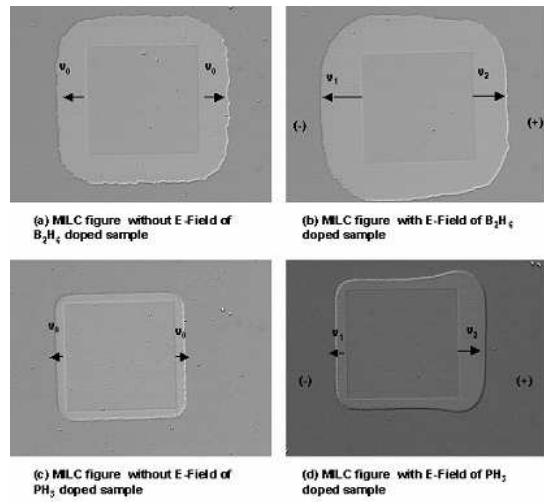


Fig. 3 MILC and FALC aspect of B₂H₆ or PH₃ doped sample